

HiRel NPN Silicon RF Transistor

• HiRel Discrete and Microwave Semiconductor

- For low noise, high-gain broadband amplifiers at cc currents from 2mA to 30mA
- Hermetically sealed microwave package
- *f*_T = 8 GHz
 - F = 2.3 dB at 2 GHz

esa Space Qualified

ESA/SCC Detail Spec. No.: 5611/006

ESD: Electrostatic discharge sensitive device, observe handling precaution!

Туре	Marking	Pin Configuration						Package
BFY 183 (ql)	-	1=C	2=E	3=B	4=E	-	-	MICRO-X1

(ql) Testing level: P: Professional testing

- H: High Rel quality
- S: Space quality
- ES: ESA qualified

Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-emitter voltage	V _{CEO}	12	V	
Collector-emitter voltage	V _{CES}	20		
Collector-base voltage	V _{CBO}	20		
Emitter-base voltage	V _{EBO}	2		
Collector current	I _C	65	mA	
Base current	I _B	51)		
Total power dissipation ²⁾	P _{tot}	450	mW	
$T_{S} \leq 99^{\circ}C$				
Junction temperature	Ti	200	°C	
Operating temperature range		-65 200	°C	
Storage temperature	T _{stg}	-65 200	°C	

Thermal Resistance

Parameter	Symbol	Value	Unit
Junction - soldering point ²⁾	R _{thJS}	< 225	K/W

¹The maximum permissible base current for V_{FBE} measurements is 20mA (spotmeasurement duration < 1s)

 $^{2}T_{S}$ is measured on the collector lead at the soldering point to the pcb



Parameter	Symbol		Values		Unit
		min.	typ.	max.	
DC Characteristics					
Base-emitter forward voltage	V _{FBE}	-	-	1	V
<i>I</i> _E = 30 mA, <i>I</i> _C = 0					
Collector-emitter cutoff current	I _{CEX}	-	-	300	μA
$V_{\rm CE} = 12 \text{ V}, \ I_{\rm B} = 0.3 \mu \text{A}^{1)}$					
Collector -base cutoff current	I _{CBO}				μA
$V_{\rm CB} = 20 \text{ V}, \ I_{\rm E} = 0$		-	-	100	
$V_{\rm CB} = 10 \text{ V}, \ I_{\rm E} = 0$		-	-	0.05	
Emitter-base cutoff current	I _{EBO}				
$V_{\rm EB} = 2 {\rm V}, I_{\rm C} = 0$		-	-	25	
$V_{\rm EB} = 1 \text{V}, I_{\rm C} = 0$		-	-	0.5	
DC current gain	h _{FE}	55	90	160	-
$I_{\rm C} = 5 \text{ mA}, V_{\rm CE} = 6 \text{ V}$					

Electrical Characteristics at $T_A = 25^{\circ}C$, unless otherwise specified

¹This test assures $V_{(BR)CE0} > 12V$



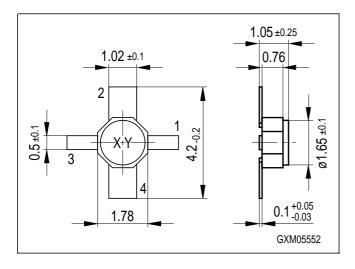
Symbol	Values			Unit
	min.	typ.	max.	
g)				1
f _T				GHz
	6.5	7.5	-	
	-	8	-	
C _{cb}	-	0.32	0.44	pF
C _{ce}	-	0.34	-	
C _{eb}	-	1.1	1.4	
F	-	2.3	2.9	dB
<i>G</i> _{ma} ¹⁾	12.5	14	-	
S _{21e} ²	9	10.5	-	dB
POUT	13.5	14.5	-	dBm
	g) f_{T} C_{cb} C_{ce} C_{eb} F $G_{ma}^{1)}$ $ S_{21e} ^2$	min. g) min. f_T 6.5 C_{Cb} - C_{cb} - C_{cb} - C_{cb} - C_{cb} - $G_{ma}^{(1)}$ 12.5 $ S_{21e} ^2$ 9	min. typ. g) f_{T} 6.5 7.5 G_{Ccb} - 0.32 C_{cb} - 0.34 C_{ce} - 1.1 F - 2.3 $G_{ma}^{1)}$ 12.5 14 $ S_{21e} ^2$ 9 10.5	min.typ.max.g) f_{T} 6.57.58-8- C_{cb} -0.320.44 C_{ce} -0.34- C_{eb} -1.11.4 F -2.32.9 $G_{ma}^{1)}$ 12.514- $ S_{21e} ^2$ 910.5-

Electrical Observatoriation at T	0500		- 11	
Electrical Characteristics at T ₄	_A = 25°C,	uniess	otherwise	specified

 ${}^{1}G_{ma} = |S_{21e} / S_{12e}| (k - (k^{2} - 1)^{1/2}), G_{ms} = |S_{21e} / S_{12e}|$



Micro-X1 Package





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